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Process For The Automatic Control Of The Thickness Of Extruded Film

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Abstract

The present invention relates to a process for the automatic control of the thickness of
15 extruded film (8). The purpose of the invention is to lower the deviations in the
thickness of the film more quickly after the start of the extrusion process.

The process involves the measurement of the thickness profile of the film (8) just
extruded by means of a thickness-measuring probe (12). The thickness-measuring
20 probe (12) is moved along the surface of the film substantially perpendicular (x) to the
conveying direction (z) of the extruded film (8). The thickness-measuring probe (12)
records a thickness profile (P) of the film (8) for each measuring cycle (MZ) at least
over parts of the expansion of the film (8) perpendicular (x) to its conveying direction
(z).

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The process pursuant to the present invention is characterized by the fact that
while providing the statistical values in relation to the older measured values the latest
measured value(s) during a predetermined time-frame at the start of the extrusion
process are more heavily weighted by the computer (14) than those measured during
30 the normal operation.

(Figure 1)